Search Notes

Ар	plication/Control No.	Applicant(s)/Patent under Reexamination	
10/	003,831	NAKANO ET AL.	
Exa	aminer	Art Unit	
_ Aa	ron W. Carter	2625	

	SEAR	CHED	
Class	Subclass	Date	Examiner
3 82	141 -		
438	16		
348	87		
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257	E23.179		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR	
EAST CLASS & TEXT SEARCH	4/05	Aux	
IEEE SEARCH	04/05	Aux	
INVENDE NAME SEARCH	4/05	Awc	